

Cypress Semiconductor Product Qualification Report

QTP# 043004 VERSION 2.0
March 2007

DDR2-PLL Device Family	
C8Q-3R, Fab 4	
CY2SSTU877	1.8V, 500-MHz, 10-Output JEDEC-Compliant Zero Delay Buffer

CYPRESS TECHNICAL CONTACT FOR QUALIFICATION DATA:

Mira Ben-Tzur
Quality Engineering Director
(408) 943-2675

Fredrick Whitwer
Principal Reliability Engineer
(408) 943-2722

PRODUCT QUALIFICATION HISTORY

Qual Report	Description of Qualification Purpose	Date Comp
042106	7C82877A DDR2 PLL New Device family on New C8Q-3R Technology, Fab4	Jan 05
050305	7C82877B DDR2 PLL All Layer Independent Mask Set on C8Q-3RQ Technology, Fab4	Mar 05
043004	Qualify Active Under Pad (AUP) for the CMI C8Q-3R Technology using DDR2 PLL Product	Nov 05

PRODUCT DESCRIPTION (for qualification)	
Qualification Purpose: Qualify Active Under Pad (AUP) for CMI C8Q-3R Technology using DDR2 PLL Product	
Marketing Part #:	CY2SSTU877
Device Description:	1.8V, Commercial/Industrial, available in 52-Ball VFBGA
Cypress Division:	Cypress Semiconductor Corporation – Consumer & Computation Division

TECHNOLOGY/FAB PROCESS DESCRIPTION C8Q-3R			
Number of Metal Layers:	4	Metal Composition:	Metal 1: 100A Ti/3,200A Al 0.5% Cu /300A TiW Metal 2: 150A Ti/4,230A Al 0.5% Cu/300A TiW Metal 3: 150A Ti/4,230A Al 0.5% Cu/300A TiW Metal 4: 150A Ti/8,000A Al 0.5% Cu/300A TiW
Passivation Type and Materials:		1,000A TEOS / 9,000A Si ₃ N ₄	
Generic Process Technology/Design Rule (μ-drawn):		CMOS, 0.13 μm	
Gate Oxide Material/Thickness (MOS):		SiO ₂ DGOX 32/55A	
Name/Location of Die Fab (prime) Facility:		CMI/Bloomington MN	
Die Fab Line ID/Wafer Process ID:		Fab4, C8Q-3R	

PACKAGE AVAILABILITY

PACKAGE	ASSEMBLY SITE FACILITY
52-Ball FBGA	ASE-Taiwan (G)

Note: Package Qualification details upon request.

MAJOR PACKAGE INFORMATION USED IN THIS QUALIFICATION	
Package Designation:	BV52
Package Outline, Type, or Name:	52-Ball Fine Ball Grid Array (FBGA)
Mold Compound Name/Manufacturer:	KMC211AA
Mold Compound Flammability Rating:	UL94 V-O
Oxygen Rating Index:	34
Lead Frame Designation:	NA
Substrate Material:	BT Resin
Lead Finish, Composition / Thickness:	SnPb
Die Backside Preparation Method/Metallization:	Backgrind
Die Separation Method:	Saw
Die Attach Supplier:	Ablebond
Die Attach Material:	8355F
Die Attach Method:	Epoxy
Bond Diagram Designation:	10-05821
Wire Bond Method:	Thermosonic
Wire Material/Size:	Au, 1.0mil
Thermal Resistance Theta JA °C/W:	80°C/W
Package Cross Section Yes/No:	No
Assembly Process Flow:	49-41023
Name/Location of Assembly (prime) facility:	ASE-TAIWAN (TAIWN-G)
MSL Level	3
Reflow Profile	220C

ELECTRICAL TEST / FINISH DESCRIPTION	
Test Location:	CML-R, CY WA

Note: Please contact a Cypress Representative for other packages availability.

RELIABILITY TESTS PERFORMED PER SPECIFICATION REQUIREMENT

Stress/Test	Test Condition (Temp/Bias)	Result P/F
High Temperature Operating Life Early Failure Rate	Dynamic Operating Condition, Vcc Max=3.8V, 125°C Dynamic Operating Condition, Vcc Max=2.35V, 125°C	P
High Temperature Operating Life Latent Failure Rate	Dynamic Operating Condition, Vcc Max=3.8V, 125°C Dynamic Operating Condition, Vcc Max=2.35V, 125°C	P
Long Life Verification	Dynamic Operating Condition, Vcc Max=3.8V, 125°C	P
Low Temperature Operating Life	-30C, 4.3V	P
High Temperature Steady State life	125°C, 3.63V, Vcc Max	P
High Accelerated Saturation Test (HAST)	130°C, 1.8V/2.35V/3.63V, 85%RH Precondition: JESD22 Moisture Sensitivity Level 3 192 Hrs, 30C/60%RH+3IR-Reflow, 220°C+0, -5°C	P
Temperature Cycle	MIL-STD-883C, Method 1010, Condition C, -65°C to 150°C Precondition: JESD22 Moisture Sensitivity Level 3 192 Hrs, 30C/60%RH+3IR-Reflow, 220°C+0, -5°C	P
Pressure Cooker	121°C, 100%RH, 15 Psig Precondition: JESD22 Moisture Sensitivity Level 3 192 Hrs, 30C/60%RH+3IR-Reflow, 220°C+0, -5°C	P
Electrostatic Discharge Human Body Model (ESD-HBM)	2,200V MIL-STD-883, Method 3015.7	P
Electrostatic Discharge Human Body Model (ESD-HBM)	2,200V JESD22, Method A114-B	P
Electrostatic Discharge Charge Device Model (ESD-CDM)	500V Cypress Spec. 25-00020	P
Age Bond Strength	200C, 4hrs MIL-STD-883, Method 883-2011	P
Ball Shear	Cypress Spec. 24-00018	P
Acoustic Microscopy	Cypress Spec. 25-00104	P
High Temperature Storage	150°C, no bias	P
Dynamic Latch up	125°C, 6.5V	P
Latch up Sensitivity	125C, ± 300mA Cypress Spec. 01-00081	P

RELIABILITY FAILURE RATE SUMMARY

Stress/Test	Device Tested/ Device Hours	# Fails	Activation Energy	Thermal ³ A.F	Failure Rate
High Temperature Operating Life Early Failure Rate ¹	3,058 Devices	0	N/A	N/A	0 PPM
High Temperature Operating Life ^{1,2} Long Term Failure Rate	651,888 DHRs	0	0.7	55	25 FIT

¹ Assuming an ambient temperature of 55°C and a junction temperature rise of 15°C.

² Chi-squared 60% estimations used to calculate the failure rate.

³ Thermal Acceleration Factor is calculated from the Arrhenius equation

$$AF = \exp \left[\frac{E_A}{k} \left[\frac{1}{T_2} - \frac{1}{T_1} \right] \right]$$

where:

E_A = The Activation Energy of the defect mechanism.

k = Boltzmann's constant = 8.62×10^{-5} eV/Kelvin.

T_1 is the junction temperature of the device under stress and T_2 is the junction temperature of the device at use conditions.

Reliability Test Data

QTP #: 042106

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC-MSL3							
CY68013A (7C681000A)	4416666	610434406	TAIWN-G	COMP	17	0	
CY2SSTU877 (7C87741A)	4416666B	H20592	TAIWN-G	COMP	16	0	
CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	COMP	17	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	COMP	16	0	
STRESS: AGE BOND STRENGTH							
CY68013A (7C681000A)	4416666	610434406	TAIWN-G	COMP	5	0	
CY68013A (7C682001A)	4416701	610437657	TAIWN-G	COMP	5	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	COMP	3	0	
STRESS: BALL SHEAR							
CY68013A (7C682001A)	4416701	610437657	TAIWN-G	COMP	5	0	
STRESS: DYNAMIC LATCH-UP TESTING (6.9V)							
CY68013A (7C682001A)	4416701	610437657	TAIWN-G	COMP	3	0	
STRESS: ESD-CHARGE DEVICE MODEL (500V)							
CY68013A (7C682001A)	4416666	610437607	TAIWN-G	COMP	9	0	
CY68013A (7C682000A)	4416666	610437102	TAIWN-G	COMP	9	0	
CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	COMP	9	0	
CY68013A (7C682000A)	4416701	610437702	TAIWN-G	COMP	9	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	COMP	9	0	
STRESS: ESD-HUMAN BODY CIRCUIT PER JESD22, METHOD A114-B, 2200V							
CY68013A (7C682001A)	4416666	610437607	TAIWN-G	COMP	9	0	
CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	COMP	9	0	
CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	COMP	9	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	COMP	9	0	
STRESS: ESD-HUMAN BODY CIRCUIT PER MIL STD 883, METHOD 3015, 2200V							
CY68013A (7C682001A)	4416666	610437607	TAIWN-G	COMP	3	0	
CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	COMP	3	0	
STRESS: HIGH TEMP STEADY STATE LIFE TEST (150C, 3.63V)							
CY68013A (7C682005A)	4416701	610438121	TAIWN-G	80	80	0	
CY68013A (7C682005A)	4416701	610438121	TAIWN-G	168	80	0	

Reliability Test Data

QTP #: 042106

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
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STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (125C, 3.8V, Vcc Max)

CY68013A (7C682001A)	4416666	610437607	TAIWN-G	96	499	0	
CY68013A (7C682005A)	4417143	610443845	TAIWN-G	96	514	0	

STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (125C, 3.8V, Vcc Max)

CY68013A (7C682001A)	4416666	610437607	TAIWN-G	168	200	0	
CY68013A (7C682001A)	4416666	610437607	TAIWN-G	1000	194	0	
CY68013A (7C682005A)	4417143	610443845	TAIWN-G	168	208	0	
CY68013A (7C682005A)	4417143	610443845	TAIWN-G	1000	208	0	

STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (125C, 2.35V, Vcc Max)

CY2SSTU877 (7C87741A)	4416666B	H20592	TAIWN-G	96	276	0	
CY2SSTU877 (7C82877A)	4416701	H20501	TAIWN-G	96	126	0	
CY2SSTU877 (7C87741A)	4416701	H20500	TAIWN-G	96	89	0	
CY2SSTU877 (7C87740A)	4416791B	H20536	TAIWN-G	96	169	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	96	304	0	
CY2SSTU877 (7C87741A)	4419587	H20650	TAIWN-G	96	500	0	

STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (125C, 3.8V, Vcc Max)

CY2SSTU877 (7C87741A)	4416666B	H20592	TAIWN-G	1000	253	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	168	150	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	1000	150	0	

STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 3.63V), PRE COND 192 HR, 30C/60%RH, MSL3

CY68013A (7C682001A)	4416666	610437607	TAIWN-G	128	47	0	
CY68013A (7C682001A)	4416666	610437607	TAIWN-G	256	47	0	
CY68013A (7C682000A)	4416701	610437702	TAIWN-G	128	47	0	
CY68013A (7C682000A)	4416701	610437702	TAIWN-G	256	45	0	

STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 1.8V), PRE COND 192 HR, 30C/60%RH, MSL3

CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	128	43	0	
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STRESS: LOW TEMPERATURE OPERATING LIFE (-30C, 4.3V)

CY68013A (7C682005A)	4416701	610438121	TAIWN-G	500	80	0	
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STRESS: STATIC LATCH-UP TESTING (125C, 5.5V, ±300mA)

CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	COMP	3	0	

Reliability Test Data

QTP #: 042106

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
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STRESS: STATIC LATCH-UP TESTING (125C, 6.5V, ±300mA)

CY68013A (7C682001A)	4416666	610437607	TAIWN-G	COMP	3	0	
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STRESS: STATIC LATCH-UP TESTING (125C, 7.5V, ±300mA)

CY68013A (7C682001A)	4416701	610437657	TAIWN-G	COMP	3	0	
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STRESS: HIGH TEMPERATURE STORAGE, 150C, no bias

CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	500	50	0	
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CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	1000	50	0	
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CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	500	45	0	
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CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	1000	45	0	
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STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR, 30C/60%RH, MSL3

CY68013A (7C681000A)	4416666	610434406	TAIWN-G	168	50	0	
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CY68013A (7C681000A)	4416666	610434406	TAIWN-G	288	50	0	
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CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	168	50	0	
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CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	288	50	0	
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CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	168	47	0	
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CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	288	47	0	
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CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	168	45	0	
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CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	288	45	0	
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STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS, 30C/60%RH, MSL3

CY68013A (7C681000A)	4416666	610434406	TAIWN-G	300	50	0	
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CY68013A (7C681000A)	4416666	610434406	TAIWN-G	500	50	0	
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CY68013A (7C681000A)	4416666	610434406	TAIWN-G	1000	50	0	
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CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	168	50	0	
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CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	500	50	0	
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CY68013A (7C681000A)	4416701	610434407/8	TAIWN-G	1000	50	0	
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CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	300	46	0	
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CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	500	45	0	
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CY2SSTU877 (7C82877A)	4413035	H19747	TAIWN-G	1000	45	0	
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CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	300	45	0	
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CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	500	45	0	
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CY2SSTU877 (7C87740A)	4417143	H20549	TAIWN-G	1000	45	0	
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Reliability Test Data

QTP #: 050305

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ESD-CHARGE DEVICE MODEL (500V)							
CY2SSTU877BVXC (7C828771B)	4448054	610501198	TAIWN-G	COMP	9	0	
STRESS: ESD-HUMAN BODY CIRCUIT PER JESD22, METHOD A114-B, 2200V							
CY2SSTU877BVXC (7C828771B)	4448054	610501198	TAIWN-G	COMP	9	0	
STRESS: ESD-HUMAN BODY CIRCUIT PER MIL STD 883, METHOD 3015, 2200V							
CY2SSTU877BVXC (7C828771B)	4448054	610501198	TAIWN-G	COMP	3	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (125C, 2.35V, Vcc Max)							
CY2SSTU877BVXC (7C828771B)	4448054	610501198	TAIWN-G	96	1018	0	
STRESS: STATIC LATCH-UP TESTING (125C, 6.5V, ±300mA)							
CY2SSTU877BVXC (7C828771B)	4448054	610501198	TAIWN-G	COMP	3	0	

Reliability Test Data

QTP #: 043004

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
STRESS: ACOUSTIC, MSL3							
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	COMP	16	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	COMP	16	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	COMP	15	0	
CY2SSTU877 (7C87741A)	4423798	H20619	TAIWN-G	COMP	15	0	
CY2SSTU877 (7C87741A)	4419587	H20650	TAIWN-G	COMP	16	0	
CY2SSTU877 (7C87741A)	4419587	H20649	TAIWN-G	COMP	15	0	
STRESS: AGE BOND STRENGTH							
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4419587	H20650	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4419587	H20649	TAIWN-G	COMP	3	0	
STRESS: BOND PULL							
CY2SSTU877 (7C87741A)	4423798	H20619	TAIWN-G	COMP	3	0	
STRESS: ESD-HUMAN BODY CIRCUIT PER JESD22, METHOD A114-B, 2200V							
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	COMP	9	0	
CY2SSTU877 (7C87741A)	4416701	H20500	TAIWN-G	COMP	9	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	COMP	9	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	COMP	9	0	
STRESS: ESD-HUMAN BODY CIRCUIT PER MIL STD 883, METHOD 3015, 2200V							
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4416701	H20500	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	COMP	3	0	

Reliability Test Data

QTP #: 043004

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (125C, 2.35V, Vcc Max)							
CY2SSTU877 (7C87741A)	4416701	H20500	TAIWN-G	96	89	0	
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	96	134	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	96	276	0	
CY2SSTU877 (7C87740A)	4416791B	H20536	TAIWN-G	96	69	0	
CY2SSTU877 (7C87741A)	4417143	H20548	TAIWN-G	96	175	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	96	304	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	96	406	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	96	434	0	
CY2SSTU877 (7C87741A)	4423798	H20619	TAIWN-G	96	671	0	
CY2SSTU877 (7C87741A)	4419587	H20650	TAIWN-G	96	500	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (125C, 2.35V, Vcc Max)							
CY2SSTU877 (7C87740A)	4416791B	H20536	TAIWN-G	168	166	0	
CY2SSTU877 (7C87741A)	4417143	H20548	TAIWN-G	168	175	0	
CY2SSTU877 (7C87741A)	4417143	H20548	TAIWN-G	1000	175	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	1000	196	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	1000	253	0	
STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 1.8V), PRE COND 192 HR, 30C/60%RH, MSL3							
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	128	46	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	128	43	0	
STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 2.35V), PRE COND 192 HR, 30C/60%RH, MSL3							
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	128	46	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	128	45	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	128	46	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	128	46	0	

Reliability Test Data

QTP #: 043004

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: HIGH TEMPERATURE STORAGE, 150C, no bias							
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	500	47	0	
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87742A)	4413035	H19746	TAIWN-G	500	46	0	
CY2SSTU877 (7C87742A)	4413035	H19746	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	500	46	0	
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	500	46	0	
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	500	45	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	1000	45	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	500	46	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	500	46	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	500	46	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	1000	46	0	
STRESS: STATIC LATCH-UP TESTING (125C, 5.5V, ±300mA)							
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4416701	H20500	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	COMP	3	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	COMP	3	0	

Reliability Test Data

QTP #: 043004

<i>Device</i>	<i>Fab Lot #</i>	<i>Assy Lot #</i>	<i>Assy Loc</i>	<i>Duration</i>	<i>Samp</i>	<i>Rej</i>	<i>Failure Mechanism</i>
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS, 30C/60%RH, MSL3							
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	300	46	0	
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	500	46	0	
CY2SSTU877 (7C87742A)	4413035	H19746	TAIWN-G	300	47	0	
CY2SSTU877 (7C87742A)	4413035	H19746	TAIWN-G	500	47	0	
CY2SSTU877 (7C87742A)	4413035	H19746	TAIWN-G	1000	47	0	
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	300	46	0	
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	500	46	0	
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	300	47	0	
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	500	46	0	
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	300	46	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	500	46	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	300	46	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	500	45	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	300	46	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	500	46	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	1000	46	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	300	46	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	500	46	0	
CY2SSTU877 (7C87741A)	4423798	H20619	TAIWN-G	300	347	0	
CY2SSTU877 (7C87741A)	4423798	H20619	TAIWN-G	500	346	0	
CY2SSTU877 (7C87741A)	4423798	H20619	TAIWN-G	1000	346	0	
CY2SSTU877 (7C87741A)	4419587	H20650	TAIWN-G	300	348	0	
CY2SSTU877 (7C87741A)	4419587	H20650	TAIWN-G	500	348	0	
CY2SSTU877 (7C87741A)	4419587	H20650	TAIWN-G	1000	348	0	

Reliability Test Data

QTP #: 043004

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15, Psig, PRE COND 192 HR, 30C/60%RH, MSL3							
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	168	47	0	
CY2SSTU877 (7C87740A)	4416701	H20499	TAIWN-G	288	47	0	
CY2SSTU877 (7C87742A)	4413035	H19746	TAIWN-G	168	46	0	
CY2SSTU877 (7C87742A)	4413035	H19746	TAIWN-G	288	46	0	
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	168	46	0	
CY2SSTU877 (7C87742A)	4416666	H20591	TAIWN-G	288	46	0	
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	168	47	0	
CY2SSTU877 (7C87741A)	4416666	H19775	TAIWN-G	288	47	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	168	46	0	
CY2SSTU877 (7C87741A)	4416666B	H20591	TAIWN-G	288	46	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	168	46	0	
CY2SSTU877 (7C87741A)	4417975	H20583	TAIWN-G	288	46	0	
CY2SSTU877 (7C87742A)	4417975	H20585	TAIWN-G	240	45	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	168	46	0	
CY2SSTU877 (7C87742A)	4423798	H20626	TAIWN-G	288	46	0	